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**DTIC STINET** 

(Citations of Defense Technical Information Center scientific and technical documents)

**EEDD Submission Form** 

Examiners' Electronic Digest Database (EEDD)

(Database of examiner submitted NPL)

**GrayLIT Network** 

(Multidisciplinary database of scientific and technical information from DTIC, NASA, DOE, and

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(Full page images of over 800,000 Electrical & Electronic Engineering articles, papers and standards, 1988 - present. Select content is available from 1952-1987.)

**INSPEC** 

(Seven million well-indexed physics, EE, and IT abstracts, 1969-present)

IP.com

(Defensive disclosures published to the Disclosures IP.com database from various websites)

NTIS (National Technical Information Service)

(resource for government-funded scientific, technical, engineering, and business related information)

**ProQuest Digital Dissertations** 

**Proquest Direct** 

(Multidisciplinary subject coverage)

Readers' Guide to Periodical Literature

(citations to popular multidisciplinary magazines)

# Research Disclosure

(Published monthly as a paper journal and now as an online database product with advanced full text searching capabilities for defensive disclosure information.)

#### ScienceDirect [Search Guide]

(scientific, technical, and medical journals)

Software Patent Institute (SPI) (Select "Free Access")

(Searchable database of Software Technologies.)

# **SPIE Digital Library**

(journals and proceedings on optics and photonics)

# STN on the Web (training and password required)

(The other link is via the Patent Examiner's Toolkit. On your computer, click on the START button, then on the PE Toolkit, then on STN Express.)

#### **True Query**

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Safari Online Books

(Computer and information technology)

Springer Publishing Company

(biotech, physics, and computer journals)

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Fulltext newspaper articles are available electronically in Proquest Direct.

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Older full text NPL resources/articles received in CD-Rom format. These resources are available on EIC2100 PCs in CPK2, 4B40.

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Power Mac G3

**Photocopier** 

#### **Reference Tools**

#### Bartleby.com

(Several versions of Roget's Thesaurus, a dictionary, an encyclopedia, quotations, English usage books and more.)

#### Computer References

(Dictionaries, Acronyms Finders, Encyclopedias)

#### Efunda

(30,000 pages of engineering fundamentals and calculators)

Encyclopedia Britannica

**Encyclopedia of Software Engineering** 

Eric Weisstein's World of Mathematics

(A comprehensive online encyclopedia of mathematics.)

**HowStuffWorks** 

(Search a term to find articles that explain how it works.)

The Internet Encyclopedia

Over 2000 Glossary Links

(Links to numerous technical, specialty, and general glossaries.)

**PCWebopedia** 

Wiley Encyclopedia of Electrical and Electronics Engineering

Yourdictionary.com

(Numerous "specialty dictionaries"... technological, law, business related and more.)

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A Brief History of the Hard Disk Drive

CiteSeer (ResearchIndex)

(Full text scientific research papers - in pdf and postscript formats.)

Interfacebus.com

(Listing of Electronic Interface Buses with links to standards and specifications.)

Internet Engineering Task Force

(The IETF Secretariat, run by The Corporation for National Research Initiatives with funding from the US government, maintains an index of Internet-Drafts.)

Nanotechnology

PCI Specifications (username: uspto; password: pat222)

("Peripheral Component Interconnect" specifications and white papers.)

Requests for Comments (RFCs) Database

(Requests for Comments (RFC) document series is a set of technical and organizational notes about the Internet (originally the ARPANET), beginning in 1969 and discussing many aspects of computer networking, including protocols, procedures and concepts as well as meeting notes and opinions.)

- **⇒** Usenet Archive (Google Groups)
- Wayback Machine

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